## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination RABIPOUR ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0135376 A1	07-2003	Harada, Yutaka	704/275
*	В	US-5,933,487 A	08-1999	Strickland, David	379/209.01
*	O	US-6,600,738 B1	07-2003	Alperovich et al.	370/352
*	۵	US-6,721,269 B2	04-2004	Cao et al.	370/227
*	ш	US-2006/0046658 A1	03-2006	Cruz et al.	455/067.11
k	F	US-6,985,530 B1	01-2006	Zerbe, Nathan B.	375/240.29
k	G	US-6,885,638 B2	04-2005	Xu et al.	370/230
k	Ι	US-2003/0072273 A1	04-2003	Aiello et al.	370/310.2
k	-	US-6,353,666 B1	03-2002	Henderson et al.	379/229
*	7	US-2004/0100914 A1	05-2004	Hellwig et al.	370/254
	К	US-			
	L	US-	P N	( )	
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.